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Complete if Known Substitute for form 1449A/PTO **Application Number** 10,724,113 INFORMATION DISCLOSURE Filing Date December 1, 2003 STATEMENT BY APPLICANT Moshe FINAROV et al. First Named Inventor 2077 2886 Group Art Unit (use as many sheets as necessary) **Examiner Name** R. Punnoose Sheet FINAROV=3A of 1 **Attorney Docket Number**

		Cite	Document Number Number-Kind Code ² (Introduct)	Publication Date	TENT DOCUMENTS Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant
Exam Initials		No.1	Number-kind Code	WIIVI-OU-TTTT		Figures Appear
7.	RP	AA	US-5,007,708	April 16, 1991	GAYLORD et al.	
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		FOREN	N PATENT DO	CUMENTS		
Examiner Initials*	Cite No.1	Foreign Patent Number Country Code ³ Number ⁸ Kind Code ³ (if known)	Poblication Date MM-SD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	76
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Examiner Signature	/Roy Punnoose/	Date Considered	04/01/2007

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PTO/SB/08b (08-03)
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Complete If Known Substitute for form 1449A/PTO 10,724,113 Application Number INFORMATION DISCLOSURE December 1, 2003 Filing Date STATEMENT BY APPLICANT Moshe FINAROV et al. First Named Inventor 2877 2886 Group Art Unit (use as many sheets as necessary) R.Punnoose **Examiner Name** Sheet 2 of 2 Attorney Docket Number FINAROV=3A

			OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	_
Examiner Initials*		Cite No.1	Include name of the author (in CAPITAL LETTERS), title of article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	
RP		AH	N. CHATEAU et al, "Algorithm for the rigorous coupled-wave analysis of grating diffraction", Journal of the Optical Society of America A, vol. 11, no. 4, April 1994, pp 1321-1331	
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	_	AN	S. LEE et al, "More stable algorithm for rigorous coupled wave analysis applied to topography simulation in optical lithography and its numerical implementation", Optical Microlithography IX, SPIE, vol. 2726, 13-15 March 1996, pp 288-298	
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			D. MILLS et al, "Spectral ellipsometry on patterned wafers", Process, Equipment, and Materials Control in Integrated Circuit Manufacturing, SPIE vol. 2637, 25-26 October 1995, pp 194-203	
			S. PENG et al, "Efficient implementation of rigorous coupled-wave analysis for surface-relief gratings", <i>J. Opt. Soc. Am. A</i> , vol. 12, no. 5, May 1995, pp 1087-1096	
			D. ZIGER et al, "Linesize effects on ultraviolet reflectance spectra", Optical Engineering, January 1997, vol. 36, no. 1, pp 243-250	
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Examiner /Roy Punnoose/	Date Considered	04/01/2007
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¹ Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.

PTO/SB/08A (10-96)

Substitute for form 1449A/PTO Complete if Kn wn **Application Number** 09/610,889 INFORMATION DISCLOSURE Filing Date July 6, 2000 STATEMENT BY APPLICANT **First Named Inventor** FINAROV et al. **Group Art Unit** 2886 (use as many sheets as necessary) **Examiner Name** R. Punnoose Sheet of 2 **Attorney Docket Number** FINAROV=3

				U.S. PATENT DOCU	MENTS	
xaminer nitials*	Cite No.1	U.S. Patent Number	Document Kind Code ² (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
RP	AA	4,905,170		FOROUHI et al.	Feb. 27, 1990	Taranta i garos repeat
	AB	5,361,137		ATON et al.	Nov. 1, 1994	
	AC	4,330,213		KLEINKNECHT et al.	May 18, 1982	
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	АН	4,710,642		MCNEIL	Dec. 1, 1987	
RP	Al	5,887,276		MCNEIL et al.	Feb. 2, 1999	
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¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the Indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

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	RMATION I			Filing Date	July 6, 2000	
STAT	EMENT BY	'AP	PLICANT	First Named Inventor	FINAROV et al.	
				Group Art Unit	2886	
	(use as many she	ets as n	ecessary)	Examiner Name	R.Punnoose	
Sheet	2	of	2	Attorney Docket Number	FINAROV=3	

		OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	
	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T²
	AJ	VOSKOVTSOVA et al., Soviet Journal of Optical Technology, (1993) vol.60, no.9, pp.617-619	
	AR	ROGER et al, "Inverse scattering method in electromagnetic optics: Applications to diffraction grating", <u>J. Opt.</u> <u>Soc. Am.</u> , (1980), vol.70, No. 12, pp.1483-1495, Optical Society of America	
,	AL	ROGER et al., "The perfectly conducting grating from the point of view of inverse diffraction", Optica Acta, (1979), vol.26, No. 3, pp.447-460, Taylor & Francis Ltd.	
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	AN	LOCHBIHLER et al., "Reconstruction of the profile of gold wire gratings: A comparison of different methods", Optik, (1994), vol.98, No.1, pp.21-25, Germany	
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	AR	MOHARAM et al., "Rigorous coupled-wave analysis of planar-grating diffraction", <u>Journal of the Optical Society of America</u> , (1981), vol.71, No. 7, pp.811-818, Optical Society of America	
	AS	RAYMOND et al., "Resist and etched line profile characterization using scatterometry", CPIE, (1997), vol.3050, pp.476-486	
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Substitute for form 14	49A/PTO	-	Complete if Known		
	_	_	Application Number	09/610,889	
INFORMA'	TION DISC	LOSURE	Filing Date	July 6, 2000	
STATEME	NT BY AP	PLICANT	First Named Inventor	Moshe FINAROV	
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Sheet 1	of	1	Attorney Docket Number	FINAROV=3	

				U.S. PATENT DOCU	MENTS	
Examiner Initials*	Cite No:1	U.S. Patent Number	Document Kind Code ⁴ (if known)	Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
RP	AU	6,045,433		DVIR et al.	04-04-2000	
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RP	AW	. 5,867,590		EYLON	02-02-1999	
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